

<b>Notice of References Cited</b>			Application/Control No. 10/786,031	Applicant(s)/Patent Under Reexamination OWEN ET AL.	
			Examiner <i>KA</i> Kamran Afshar, 571-272-7796	Art Unit 2617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0173295 A1	11-2002	Nykanen et al.	455/414
*	B	US-2004/0088550 A1	05-2004	Maste, Rolf	713/182
*	C	US-2004/0127190 A1	09-2003	Hansson et al.	455/418
*	D	US-2005/0101309 A1	05-2005	Croome, Martin	455/418
*	E	US-2003/0177248 A1	09-2003	Brown et al.	709/229
*	F	US-2003/0217171 A1	11-2003	Von Stuermer et al.	709/231
*	G	US-2005/0215236 A1	09-2005	Myka et al.	455/414.1
*	H	US-2004/0082361 A1	04-2004	Rajagopalan, Bala	455/550.1
*	I	US-2004/0152457 A1	01-2003	Goldstein et al.	455/419
*	J	US-2003/0092434 A1	05-2003	Irisawa, Kazuyoshi	455/418
*	K	US-2004/0085970 A1	05-2004	Kang, Eun-jin	370/400
*	L	US-2003/0181196 A1	09-2003	Davidov et al.	455/418
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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